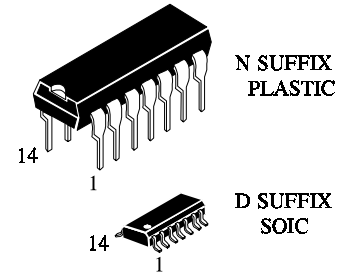


**IN74LS06**

## Hex Inverted Buffers with Open-Collector Outputs

This device contains hex inverted buffers with open-collector. It performs the Boolean function  $Y = \overline{A}$  in positive Logic.

- High Output Voltage (30 V)
- High Speed (  $t_{PD} = 8.5$  ns typical)
- Low Power Dissipation ( $P_D = 18$  mW per Gate)

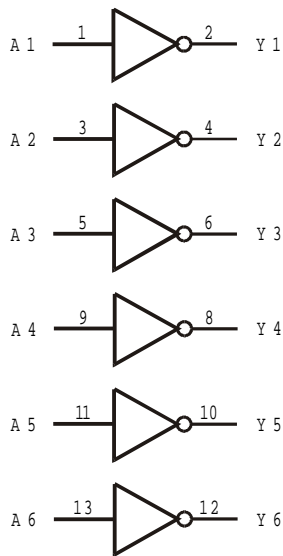


**ORDERING INFORMATION**

IN74LS06N Plastic  
IN74LS06D SOIC

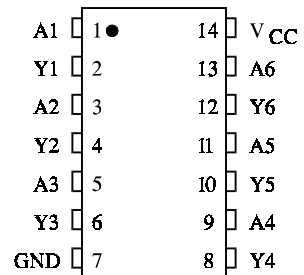
$T_A = 0^\circ$  to  $70^\circ$  C for all packages

**LOGIC DIAGRAM**



PIN 14 =  $V_{CC}$   
PIN 7 = GND

**PIN ASSIGNMENT**



**FUNCTION TABLE**

| Inputs | Output |
|--------|--------|
| A      | Y      |
| H      | L      |
| L      | H      |

**MAXIMUM RATINGS\***

| Symbol           | Parameter                 | Value       | Unit |
|------------------|---------------------------|-------------|------|
| V <sub>CC</sub>  | Supply Voltage            | 7.0         | V    |
| V <sub>IN</sub>  | Input Voltage             | 5.5         | V    |
| V <sub>OUT</sub> | Output Voltage            | 30          | V    |
| T <sub>stg</sub> | Storage Temperature Range | -65 to +150 | °C   |

\*Maximum Ratings are those values beyond which damage to the device may occur. Functional operation should be restricted to the Recommended Operating Conditions.

**RECOMMENDED OPERATING CONDITIONS**

| Symbol          | Parameter                 | Min  | Max  | Unit |
|-----------------|---------------------------|------|------|------|
| V <sub>CC</sub> | Supply Voltage            | 4.75 | 5.25 | V    |
| V <sub>IH</sub> | High Level Input Voltage  | 2.0  |      | V    |
| V <sub>IL</sub> | Low Level Input Voltage   |      | 0.8  | V    |
| V <sub>OH</sub> | High Level Output Voltage |      | 30   | V    |
| I <sub>OL</sub> | Low Level Output Current  |      | 40   | mA   |
| T <sub>A</sub>  | Ambient Temperature Range | 0    | +70  | °C   |

**DC ELECTRICAL CHARACTERISTICS** over full operating conditions

| Symbol          | Parameter                 | Test Conditions                                 | Guaranteed Limit        |      | Unit |    |
|-----------------|---------------------------|---|-------------------------|------|------|----|
|                 |                           |   | Min                     | Max  |      |    |
| V <sub>IK</sub> | Input Clamp Voltage       | V <sub>CC</sub> = min, I <sub>IN</sub> = -18 mA |                         | -1.5 | V    |    |
| I <sub>OH</sub> | High Level Output Current | V <sub>CC</sub> = min, V <sub>OH</sub> = max    |                         | 250  | μA   |    |
| V <sub>OL</sub> | Low Level Output Voltage  | V <sub>CC</sub> = min, I <sub>OL</sub> = 16 mA  |                         | 0.4  | V    |    |
|                 |                           | V <sub>CC</sub> = min, I <sub>OL</sub> = 40 mA  |                         | 0.7  |      |    |
| I <sub>IH</sub> | High Level Input Current  | V <sub>CC</sub> = max, V <sub>IN</sub> = 2.7 V  |                         | 20   | μA   |    |
|                 |                           | V <sub>CC</sub> = max, V <sub>IN</sub> = 5.5 V  |                         | 1    | mA   |    |
| I <sub>IL</sub> | Low Level Input Current   | V <sub>CC</sub> = max, V <sub>IN</sub> = 0.4 V  |                         | -0.2 | mA   |    |
| I <sub>CC</sub> | Supply Current            | V <sub>CC</sub> = max                           | Total with outputs high |      | 18   | mA |
|                 |                           |   | Total with outputs low  |      | 60   |    |

**AC ELECTRICAL CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V}$ ,  $C_L = 15\text{ pF}$ ,  
 $R_L = 110\ \Omega$ ,  $t_r = 15\text{ ns}$ ,  $t_f = 6.0\text{ ns}$ )

| Symbol    | Parameter                              | Min | Max | Unit |
|-----------|--|-----|-----|------|
| $t_{PLH}$ | Propagation Delay, Input A to Output Y |     | 15  | ns   |
| $t_{PHL}$ | Propagation Delay, Input A to Output Y |     | 20  | ns   |

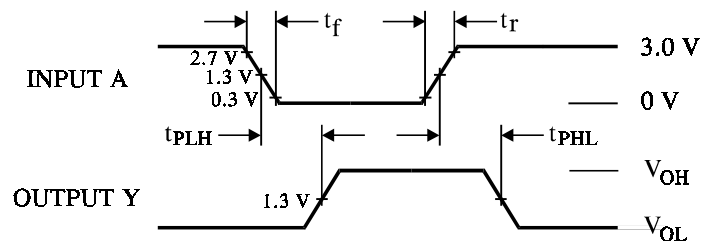
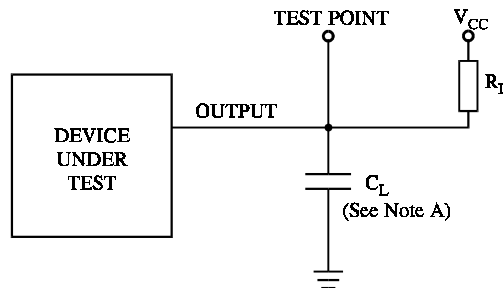


Figure 1. Switching Waveforms



NOTE A.  $C_L$  includes probe and jig capacitance.

Figure 2. Test Circuit